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L14	L13 and (delay\$4 near2 clos\$4)	11	L14
L13	L12 and (flag or identifier)	1563	L13
L12	L11 and file and cach\$5	1999	L12
L11	open\$4 and clos\$4 and command\$4 and shar\$4	20930	L11
L10	cach with file with open	4	L10
L9	(shar\$4 with violat\$4 with file)	10	L9
L8	(shar\$4 with violat\$4) and casualt\$4	0	L8
L7	((shar\$4 with violat\$4) and casualt\$4)	0	L7
L6	(shar\$4 with violat\$4 with casualt\$4)	0	L6
L5	((shar\$4 with violation) and file and delet\$4 and renam\$5)	5	L5
L4	scavenger adj1 list	3	L4
L3	(cach\$4 with file with open).ab.	5	L3
L2	L1 and (707/\$.ccls.)	22	L2
L1	scavenger	18952	L1

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L1	scavenger	18952	L1

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scavenger

**Results:**Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD****1 Streamer inception and propagation in insulating liquids with inserted scavenger electrodes**

*Badent, R.; Julliard, Y.; Kist, K.; Schwab, A.J.;*  
Electrical Insulation and Dielectric Phenomena, 2000 Annual Report  
Conference on , Volume: 1 , 15-18 Oct. 2000  
Page(s): 268 -271 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(484 KB\)\]](#) **IEEE CNF****2 Effectors of high temperature reliability in epoxy encapsulated devices**

*Gallo, A.A.;*  
Electronic Components and Technology Conference, 1993.  
Proceedings., 43rd , 1-4 June 1993  
Page(s): 356 -366

[\[Abstract\]](#) [\[PDF Full-Text \(492 KB\)\]](#) **IEEE CNF****3 Development of conductive adhesives for solder replacement**

*Daoqiang Lu; Wong, C.P.;*  
Components and Packaging Technologies, IEEE Transactions on [see also Components, Packaging and Manufacturing Technology, Part A: Packaging Technologies, IEEE Transactions on] , Volume: 23 Issue: 4 , Dec. 2000  
Page(s): 620 -626

[\[Abstract\]](#) [\[PDF Full-Text \(124 KB\)\]](#) **IEEE JNL**

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- [Tables of Contents](#)
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- [Basic](#)
- [Advanced](#)

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